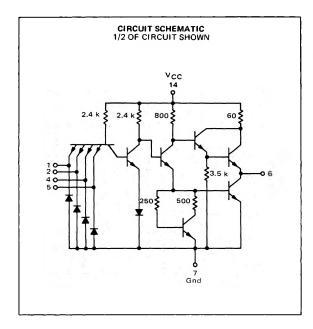
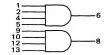
DUAL 4-INPUT "AND" GATE

MC3111F • MC3011F MC3111L • MC3011L,P (54H21J) (74H21J,N)



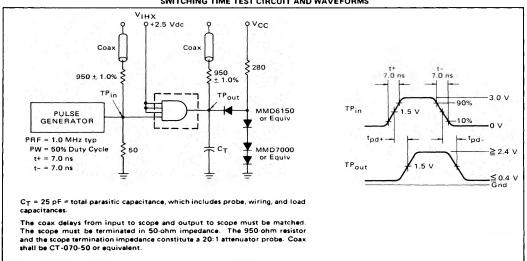
This device consists of two 4-input AND gates. This non-inverting function is useful for optimizing logic design, or for direct implementation of standard logic equations.



Positive Logic: $6 = 1 \cdot 2 \cdot 4 \cdot 5$ Negative Logic: 6 = 1 + 2 + 4 + 5

Input Loading Factor = 1 Output Loading Factor = 10 Total Power Dissipation = 56 mW typ/pkg Propagation Delay Time = 9.0 ns typ

SWITCHING TIME TEST CIRCUIT AND WAVEFORMS



ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one gate. The other gate is tested in the same manner. Further, test procedures are shown for only one input of the gate under test.

To complete testing, sequence through remaining inputs.

															_						2	UKKEN	I VOLIAL	IEST CURRENT/ VOLTAGE VALUES						
														(6)	Toct @		=	mA						Vo	Volts					
														Tempe	Temperature	lor	НОН	-i	٩	ν'n	× H	٧,	۸ «	× ₽¥	V _{mem}	V _{CC}	VccL	VCCH	VIIX	
														_	−55°C	20	-2.0		-	1.1	2.0 0	0.4	2.4	4.0		5.0	4.5	5.5	,	
													MC3111	~	+25°C	20	-2.0	1.0	-10	1.1	1.8 0	0.4	2.4	4.0	0.7	5.0	4.5	5.5	2.5	
														ţ	+125°C	20	-2.0	-		8.0	1.8 0	9.4	2.4	4.0		5.0	4.5	5.5	,	
														-	၁့၀	20	-2.0			1.1	2.0 0	0.4	2.5	4.0		5.0	4.75	5.25	,	
													MC3011	~~	+25°C	20	-2.0	1.0	-10	1.1	1.8	9.4	2.5	4.0	7.0	5.0	4.75	5.25	2.5	
	21/2				,									-	+75°C	20.	-2.0			6.0	1.8 0	0.4	2.5	4.0		5.0	4.75	5.25		
		Pin		W	MC3111 Test	est Limits	its			Ä	3011	MC3011 Test Limits	ıţs						TEST	CURREN	17 / VO	LTAGE	TEST CURRENT / VOLTAGE APPLIED T	TO PINS LISTED BELOW:	TED BEL	MO.				
		Inder	1	_55°C	+25°C	ي ر	+125°C	<u>2</u> پ	0	٥,٥	+25°C	<u>ي</u> ر	+75°C	ى ئەر					-	-	-	+	-						1	
Characteristic	Symbol	Test	Min	Max	Min Max	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit	٥_	₽	_:E	٩	>"	,±	>"	>"	V _{RH}	Vmax	ν ςς	VCCL	V _{CCH}	VIHX	Pug
Input Forward Current	I_{F}	1	1	-2.0		-2.0	,t _a	-2.0	1	-2.0		-2.0		-2.0	mAdc	,				,	,	-		2,4,5*				14		1
Leakage Current	IR	-	1	20	į.	20	1 -	20	1	20	•	20		20	дАdc	,			,			,	1	* 1		,		14		2, 4, 5, 7
Breakdown Voltage	BVin	1	i	1	5.5		1	ı	1	ı	5.5		-		Vdc			-						*				14	1	2, 4, 5, 7
Clamp Voltage	v _D	-	1	1	ı.	-1.5	i,				1	-1.5			Vdc	,		,	-		1			*			14			7
Output Output Voltage	N _{OL}	9	1	0.4		0.4		0.4		0.4		9.4		0.4	Vdc	9	,			-	-	,		2,4,5*			14			2
	, он	9	2.4		2.4		2.4		2.5		2.5		2.5		Vdc		9					-		2,4,5*			14			L
Short-Circuit Current	1sc	9	-40	-100	-40	-100	-40	-100	-40	-100	-40	-100	-40	-100	mAdc				,		,			1,2,4,5*		,	r.	14		6,7
Power Requirements (Total Device) Maximum Power Supply Current	Imax	14	, L	1	4 (P)	18		- 1	,		1	18	1	-	mAdc	1			,		,	- 1		1,2,4,5,	14		170			7
Power Supply Drain	нач	14	1	13.2		13.2	1	13.2	1,2	13.2		13.2	,	13.2	mAdc									1, 2, 4, 5, 9, 10, 12, 13		-		14		7
-	IPDL	14		26	-	26	-	26		56		26		26	mAdc		,	1.			1				,			14		1, 2, 4, 5, 7, 9, 10, 12, 13
Switching Parameters Turn-On Delay	t pd-	1,6	1		. (15	1					15		1	BS	Pulse	Pulse Out		٠.				,	*	,	14			2, 4, 5	7
Turn-Off Delay	t pd+	1,6	1			12	1				١.	12			su	-	9	1	,	1.	1.	1.		*		14			2,4,5	2

*Since this is a non-inverting gate, power drain is minimized by tying the inputs to gates not under test to $^{
m V}_{
m RH}$